

Diode

Rapid Switching Emitter Controlled Diode

IDP20E65D2

Emitter Controlled Diode

Data sheet

Industrial Power Control



Rapid Switching Emitter Controlled Diode

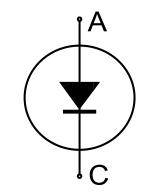
Features:

- · Qualified according to JEDEC for target applications
- 650 V Emitter Controlled technology
- Fast recovery
- Soft switching
- Low reverse recovery charge
 Low forward voltage and stable over temperature
 175 °C junction operating temperature
 Easy paralleling

- · Pb-free lead plating; RoHS compliant

Applications:

• Boost diode in CCM PFC









Key Performance and Package Parameters

Туре	V _{rrm}	I f	<i>V</i> _f , <i>T</i> _{∨j} =25°C	T _{vjmax}	Marking	Package
IDP20E65D2	650V	20A	1.6V	175°C	E20ED2	PG-TO220-2-1





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Maximum Ratings

For optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Parameter	Symbol	Value	Unit
Repetitive peak reverse voltage, <i>T</i> _{vj} ≥ 25°C	V_{RRM}	650	V
Diode forward current, limited by T_{vjmax} $T_C = 25^{\circ}C$ $T_C = 100^{\circ}C$	I _F	40.0 20.0	А
Diode pulsed current, t_p limited by T_{vjmax}	I _{Fpuls}	60.0	Α
Diode surge non repetitive forward current $T_C = 25^{\circ}C$, $t_p = 8.3$ ms, sine halfwave	I FSM	120.0	А
Power dissipation $T_C = 25^{\circ}C$	P _{tot}	120.0	W
Operating junction temperature	T _{vj}	-40+175	°C
Storage temperature	T _{stg}	-55+150	°C
Soldering temperature, wave soldering 1.6 mm (0.063 in.) from case for 10s		260	°C
Mounting torque, M3 screw Maximum of mounting processes: 3	М	0.6	Nm

Thermal Resistance

Parameter	Symbol	Conditions	Max. Value			
Characteristic	1					
Diode thermal resistance, ¹⁾ junction - case	R _{th(j-c)}		1.25	K/W		
Thermal resistance junction - ambient	R _{th(j-a)}		62	K/W		

Electrical Characteristic, at T_{vj} = 25°C, unless otherwise specified

Davamatar.	Cymahal	Canditiana	Value			11:4
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Static Characteristic			•			
Diode forward voltage	V _F	$I_F = 20.0A$ $T_{vj} = 25^{\circ}C$ $T_{vj} = 175^{\circ}C$		1.60 1.65	2.20	V
Reverse leakage current	I_{R}	$V_{R} = 650V$ $T_{vj} = 25^{\circ}C$ $T_{vj} = 175^{\circ}C$		2.0 500.0	40.0	μA

Electrical Characteristic, at T_{vj} = 25°C, unless otherwise specified

Davamatav	C. mah al	Conditions	Value			11
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Dynamic Characteristic				•		
Internal emitter inductance measured 5mm (0.197 in.) from case	LE		-	7.0	-	nH

¹⁾ Please be aware that in non standard load conditions, due to high Rth(j-c), Tvj close to Tvjmax can be reached.



Switching Characteristic, Inductive Load

Davamatav	Cymahal	Conditions	Value			Unit
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Diode Characteristic, at T_{vj} = 25°C						
Diode reverse recovery time	t _{rr}	$T_{\rm vj} = 25^{\circ}{\rm C},$	-	32	-	ns
Diode reverse recovery charge	Qrr	$V_{\rm R} = 400 \text{V},$ $I_{\rm F} = 20.0 \text{A},$	-	0.25	-	μC
Diode peak reverse recovery current	I _{rrm}	/ _F = 20.0A, di _F /dt = 1000A/μs,	-	12.2	-	Α
Diode peak rate of fall of reverse recovery current during t_b	I of reverse di/dt $L\sigma = 30$ nH,		-	-900	-	A/µs
Diode reverse recovery time	t _{rr}	T _{vi} = 25°C,	_	43	_	ns
Diode reverse recovery charge	Qrr	$V_{\rm R} = 400 \text{V},$	-	0.19	-	μC
Diode peak reverse recovery current Irrm		$I_F = 20.0A,$ $di_F/dt = 400A/\mu s,$	-	6.3	-	Α
Diode peak rate of fall of reverse recovery current during t_b	di _{rr} /dt	$L\sigma$ = 30nH, $C\sigma$ = 40pF, switch IKW50N65H5	-	-420	-	A/µs

Switching Characteristic, Inductive Load

Doromotor	Symbol	Conditions	Value		11!4	
Parameter	Symbol	Conditions	min.	typ.	max.	Unit

Diode Characteristic, at T_{vj} = 175°C/125°C

t _{rr}	$T_{\rm vj} = 175^{\circ}{\rm C},$	-	55	-	ns
Diode reverse recovery charge Q _{rr}		-	0.58	-	μC
I rrm	di _F /dt = 1000A/μs,	-	18.0	-	Α
Diode peak rate of fall of reverse recovery current during t_b di_{rr}/dt $C\sigma = 30nH$, $C\sigma = 40pF$, switch IKW50N65H5		-	-650	-	A/µs
				ı	
t _{rr}	$T_{vi} = 125^{\circ}C,$	-	61	-	ns
Q _{rr}	$V_{R} = 400V$,	ı	0.38	-	μC
I rrm	$di_{\rm F}/dt = 400 {\rm A/\mu s},$	-	9.3	-	Α
crate of fall of reverse urrent during t_b di_{rr}/dt $L\sigma = 30 nH$, $C\sigma = 40 pF$, switch IKW50N65H5		-	-500	-	A/µs
	Qrr Irrm dirr/dt trr Qrr Irrm	Q_{rr} $V_{R} = 400V$, $V_{R} = 20.0A$, $I_{F} = 20.0A$, I_{frm} I_{frm} $I_{fr} = 20.0A$, I_{frm} $I_{fr} = 30nH$, $I_{fr} = 40pF$, switch IKW50N65H5 $I_{fr} = 125^{\circ}C$, $I_{fr} = 125^{\circ}C$, $I_{fr} = 20.0A$, $I_{frm} = 125^{\circ}C$,	Q_{rr} $V_{R} = 400V$, $I_{F} = 20.0A$, I_{rrm} $di_{F}/dt = 1000A/\mu s$, $I_{C}\sigma = 30nH$, $I_{C}\sigma = 40pF$, $I_{C}\sigma = 40pF$, $I_{C}\sigma = 400V$, $I_{C}\sigma = 400V$, $I_{C}\sigma = 400V$, $I_{C}\sigma = 20.0A$, I_{rrm} $I_{C}\sigma = 30nH$, $I_{C}\sigma = 30nH$, $I_{C}\sigma = 40pF$,	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$



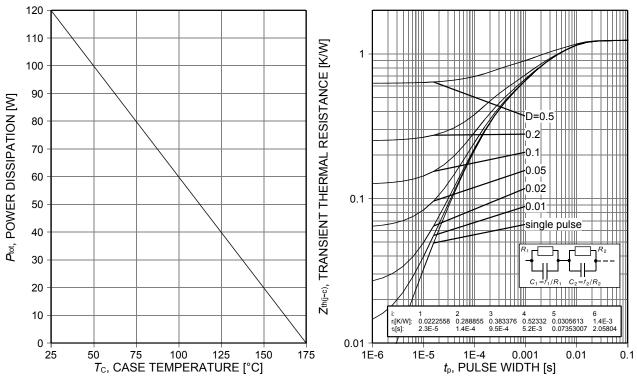


Figure 1. Power dissipation as a function of case temperature (*T*_{vj}≤175°C)

Figure 2. Diode transient thermal impedance as a function of pulse width $(D=t_p/T)$

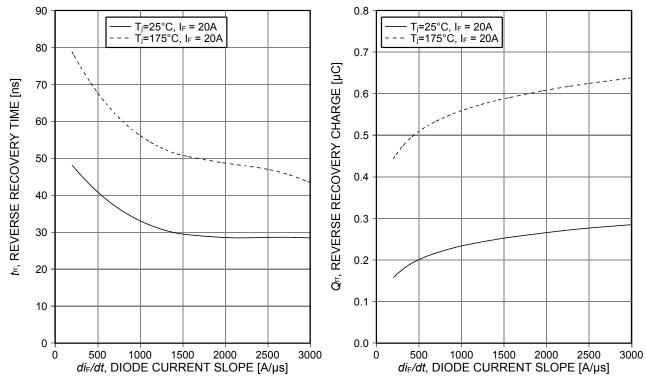


Figure 3. Typical reverse recovery time as a function of diode current slope $(V_R=400V)$ Figure 4. Typical reverse recovery charge as a function of diode current slope $(V_R=400V)$

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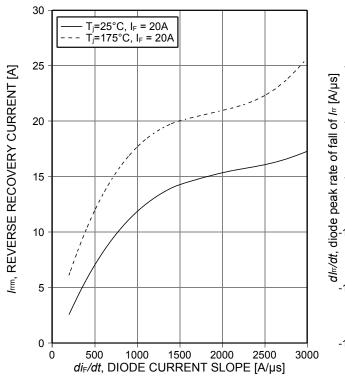


Figure 5. Typical peak reverse recovery current as a function of diode current slope $(V_R=400V)$

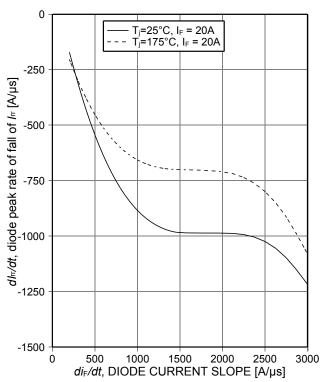
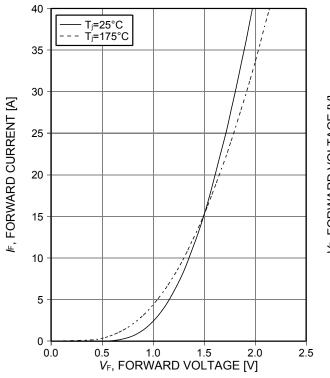


Figure 6. Typical diode peak rate of fall of reverse recovery current as a function of diode current slope $(V_R=400V)$



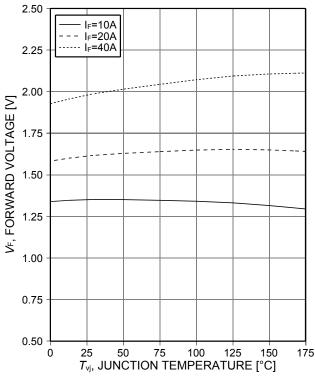
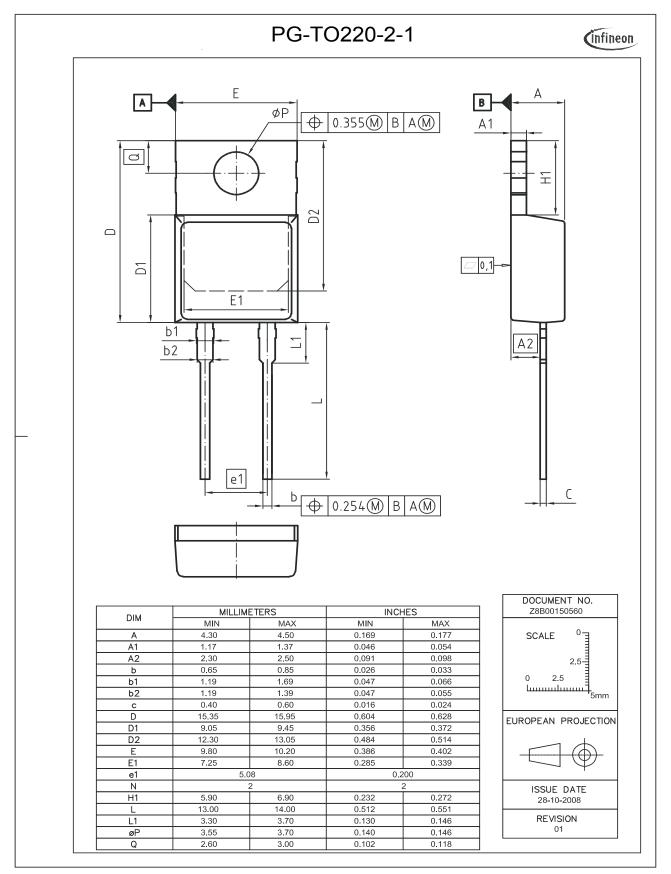


Figure 7. Typical diode forward current as a function of forward voltage as a function of junction temperature







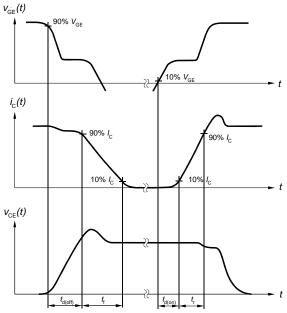


Figure A. Definition of switching times

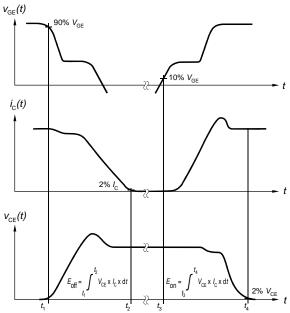


Figure B. Definition of switching losses

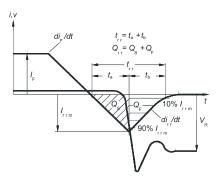


Figure C. Definition of diodes switching characteristics

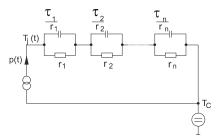


Figure D. Thermal equivalent circuit

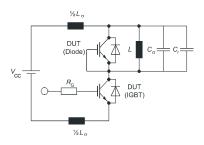


Figure E. Dynamic test circuit Parasitic inductance L_{σ} , Parasitic capacitor C_{σ} , Relief capacitor C_{r} (only for ZVT switching)



Revision History

IDP20E65D2

Revision: 2014-09-18, Rev. 2.1

Previous Revision

1 Teviodo Nevioloti							
Revision	Date	ubjects (major changes since last revision)					
2.1	2014-09-18	Final data sheet					

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